

FDP5N50NZ / FDPF5N50NZ N-Channel UniFET[™] II MOSFET 500 V, 4.5 A, 1.5 Ω

Features

- R $_{DS(on)}$ = 1.38 Ω (Typ.) @ V_{GS} = 10 V, I_D = 2.25 A
- Low Gate Charge (Typ. 9 nC)
- Low Crss (Typ. 4 pF)
- 100% Avalanche Tested
- Improved dv/dt Capability
- ESD Imoroved Capability
- RoHS Compliant

Applications

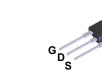
- LCD/LED TV
- Lighting
- Uninterruptible Power Supply
- AC-DC Power Supply



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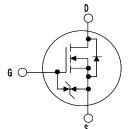
Description

UniFET[™] II MOSFET is Fairchild Semiconductor[®]'s high voltage MOSFET family based on advanced planar stripe and DMOS technology. This advanced MOSFET family has the smallest onstate resistance among the planar MOSFET, and also provides superior switching performance and higher avalanche energy strength. In addition, internal gate-source ESD diode allows UniFET II MOSFET to withstand over 2kV HBM surge stress. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.



TO-220

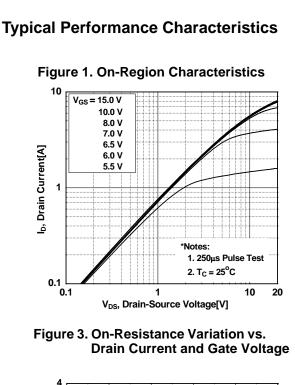


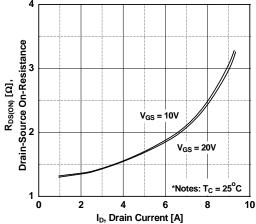


MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

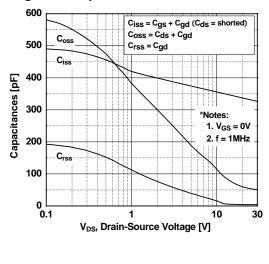
| Symbol | Parameter | | | FDP5N50NZ | FDPF5N50NZ | Unit | | |
|-----------------------------------|--|---|-----------|-------------|------------|------|--|--|
| V _{DSS} | Drain to Source Voltage | | | 5 | V | | | |
| V _{GSS} | Gate to Source Voltage | | | E | V | | | |
| I _D | Drain Current | -Continuous (T _C = 25 ^o C) | | 4.5 | 4.5* | A | | |
| | | -Continuous (T _C = 100 ^o C) | | 2.7 | 2.7* | A | | |
| I _{DM} | Drain Current | - Pulsed | (Note 1) | 18 | 18* | Α | | |
| E _{AS} | Single Pulsed Avalanche Energy (Note 2) | | | 160 | | mJ | | |
| I _{AR} | Avalanche Current (Note 1) | | | 4.5 | | Α | | |
| E _{AR} | Repetitive Avalanche Energy (Note 1) | | | - | mJ | | | |
| dv/dt | Peak Diode Recovery dv/dt (Note 3) | | 10 | | V/ns | | | |
| P _D | Power Dissipation | $(T_{\rm C} = 25^{\rm o}{\rm C})$ | | 78 | 30 | W | | |
| | | - Derate above 25°C | | 0.62 | 0.24 | W/ºC | | |
| T _J , T _{STG} | Operating and Storage Temperature Range | | | -55 to +150 | | °C | | |
| TL | Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds | | | 3 | °C | | | |
| | nited by maximum junction temperatu Characteristics | ıre | | | | | | |
| Symbol | Parameter | | FDP5N50NZ | FDPF5N50NZ | Unit | | | |
| R _{θJC} | Thermal Resistance, Junction to Case, Max. | | | 1.6 | 4.1 | | | |
| R _{0CS} | Thermal Resistance, Case to Sink Typ. | | | - | - | °C/W | | |
| $R_{\theta JA}$ | Thermal Resistance, Junctior | to Ambient, Max. | | 62.5 | 62.5 | | | |

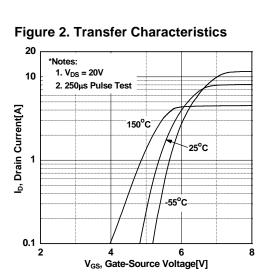
| | Device | Package | e Reel Size | Таре | e Width | | Quantit | y |
|------------------------------------|--|--|--|--|--|--|---|---|
| FDP5N50NZ FDP5N50NZ T | | TO-220 | | | - | 50 | | |
| FDPF5N50NZ FDPF5N50NZ TO-22 | | TO-220F | - | | - | | 50 | |
| l Char | acteristics T _C = | = 25ºC unless c | otherwise noted | | | | | |
| | Parameter | | Test Condition | ons | Min. | Тур. | Max. | Unit |
| teristic | S | | | | | | | |
| Drain to | Source Breakdown V | /oltage | $I_{D} = 250 \mu A, V_{GS} = 0V,$ | T _C = 25°C | 500 | - | - | V |
| | akdown Voltage Temperature | | $I_D = 250\mu A$, Referenced to $25^{\circ}C$ | | - | 0.5 | - | V/ºC |
| Zara Cr | | | $V_{DS} = 500V, V_{GS} = 0V$ | | - | - | 1 | |
| DSS Zero Gate Voltage Drain Currer | | ent | $V_{DS} = 400V, V_{GS} = 0V, T_{C} = 125^{\circ}C$ | | | - | 10 | μA |
| Gate to | to Body Leakage Current | | $V_{GS} = \pm 25V, V_{DS} = 0V$ | | - | - | ±10 | μA |
| teristic | S | | | | | | | |
| Gate Th | nreshold Voltage | | $V_{GS} = V_{DS}, I_{D} = 250 \mu A$ | | 3.0 | - | 5.0 | V |
| | | sistance | | | - | 1.38 | 1.5 | Ω |
| Forward | | | $V_{\rm DS} = 20V, I_{\rm D} = 2.25A$ | - | 3.54 | - | S | |
| haracte | vistics | | | | | | | -1 |
| | | | | | | 330 | 440 | pF |
| | t Capacitance | | $V_{DS} = 25V, V_{GS} = 0V$ f = 1MHz | | | | - | pF |
| | | | | | | | - | pF |
| | | 6 | | | | | - | nC |
| | - | | V _{DS} = 400V I _D = 4.5A | s = 400V I _D = 4.5A | - | | - | nC |
| - | 5 | | $V_{GS} = 10V$ | _ | | _ | nC | |
| | | | | (Note 4,5) | | | | |
| | | | | | | | | |
| | • | | V 250V L 454 | | - | | | ns |
| | | | $V_{DD} = 250V, I_{D} = 4.5A$ $V_{GS} = 10V, R_{GEN} = 25\Omega$ (Note 4,5) | | | | | ns |
| | | | | | | | | ns |
| Turn-Of | Fall Time | | | | - | 21 | 50 | ns |
| ce Dio | de Characteristic | s | | | | | | |
| Maximu | mum Continuous Drain to Source Diode Forward Current | | | | - | - | 4.5 | Α |
| | num Pulsed Drain to Source Diode Fo | | | | - | - | 18 | Α |
| Drain to | Source Diode Forwar | d Voltage | $V_{GS} = 0V, I_{SD} = 4.5A$ | | - | - | 1.4 | V |
| Reverse | Recovery Time | | $V_{GS} = 0V, I_{SD} = 4.5A$ | | - | 210 | - | ns |
| Reverse | Recovery Charge | | dl _F /dt = 100A/µs | (Note 4) | - | 1.1 | - | μC |
| | I Char Eteristic Drain to Breakdo Coeffici Zero Ga Gate to Eteristic Gate Th Static D Forward Characte Total Ga Gate to Gate to Charac Charac Charac Turn-Or Turn-Or Turn-Or Turn-Off Tu | I Characteristics T _C = Parameter Eteristics Drain to Source Breakdown V Breakdown Voltage Temperat Coefficient Zero Gate Voltage Drain Curre Gate to Body Leakage Currer Eteristics Gate Threshold Voltage Static Drain to Source On Re Forward Transconductance Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitanc Total Gate Charge at 10V Gate to Source Gate Charge Gate to Drain "Miller" Charge Characteristics Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time rce Diode Characteristic Maximum Continuous Drain to Maximum Pulsed Drain to Source | I Characteristics T _C = 25°C unless of Parameter teristics Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Body Leakage Current teristics Gate Threshold Voltage Static Drain to Source On Resistance Forward Transconductance Characteristics Input Capacitance Output Capacitance Total Gate Charge at 10V Gate to Source Gate Charge Gate to Drain "Miller" Charge Characteristics Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time rce Diode Characteristics Maximum Continuous Drain to Source Diode Forward Voltage Reverse Recovery Time | I Characteristics Test Condition Parameter Test Condition Iteristics Indication Drain to Source Breakdown Voltage Indication Breakdown Voltage Temperature Coefficient Indication Zero Gate Voltage Drain Current Visc = 500V, Visc = 0V, Visc = 0V, Visc = 400V, Visc = 25V, Visc = 0V Static Drain to Source On Resistance Visc = 10V, Indication Static Drain to Source On Resistance Visc = 20V, Indication Forward Transconductance Visc = 25V, Visc = 0V Characteristics Input Capacitance Visc = 25V, Visc = 0V Input Capacitance Visc = 25V, Visc = 0V f = 1MHz Characteristics Visc = 10V g = 400V Iii = 4.5A Gate to Drain "Miller" Charge Visc = 10V G = 10V Characteristics Visc = 10V, Iii = 4.5A Visc = 10V, Iii = 4.5A Turn-On Delay Time Visc = 10V, Rigen = 250 Visc = 10V, Rigen = 250 Turn-Off Fall Time Visc = 00V, Iii = 4.5A Visc = 00V, Iii = 4.5A Maximum Continuous Drain to Source Diode Forward Current Maximum Pulsed Drain to Source Diode Forward Current | I Characteristics $T_c = 25^{\circ}C$ unless otherwise noted Parameter Test Conditions tteristics Ip = 250 \muA, V_{GS} = 0V, T_c = 25^{\circ}C Breakdown Voltage Temperature Coefficient Ip = 250 \muA, Referenced to 25^{\circ}C Zero Gate Voltage Drain Current $V_{DS} = 500V, V_{GS} = 0V$ Zero Gate Voltage Drain Current $V_{GS} = 400V, V_{GS} = 0V, T_c = 125^{\circ}C$ Gate to Body Leakage Current $V_{GS} = 10V, I_D = 250\mu$ A Static Drain to Source On Resistance $V_{GS} = 10V, I_D = 2.25A$ Forward Transconductance $V_{DS} = 20V, I_D = 2.25A$ (Note 4) Characteristics Input Capacitance $V_{DS} = 25V, V_{GS} = 0V$ (Note 4) Characteristics Volute Capacitance $V_{DS} = 400V I_D = 4.5A$ (Note 4.5) Characteristics V_{DD} = 250V, V_{GS} = 10V (Note 4.5) (Note 4.5) Characteristics V_{DD} = 250V, V_{GS} = 10V (Note 4.5) Characteristics V_{DD} = 250V, I_D = 4.5A (Note 4.5) Characteristics V_{DD} = 250V, I_D = 4.5A (Note 4.5) Characteristics Maximum Continuous Drain to Source Diode Forward Current (Note 4.5) Characteristics Maximum Continuous Drain to Source Diode Forwa | I Characteristics T _C = 25°C unless otherwise noted Parameter Test Conditions Min. Iteristics Drain to Source Breakdown Voltage I _D = 250µA, V _{GS} = 0V, T _C = 25°C 500 Breakdown Voltage Temperature Coefficient I _D = 250µA, Referenced to 25°C - Zero Gate Voltage Drain Current $V_{DS} = 500V, V_{GS} = 0V$ - Gate to Body Leakage Current $V_{GS} = 400V, V_{GS} = 0V, T_C = 125°C$ - Gate to Body Leakage Current $V_{GS} = 400V, V_{GS} = 0V, T_C = 125°C$ - Gate to Body Leakage Current $V_{GS} = 400V, V_{GS} = 0V, T_C = 125°C$ - Gate Threshold Voltage $V_{GS} = 400V, V_{GS} = 0V, T_C = 125°C$ - Gate Threshold Voltage $V_{GS} = 400V, V_{GS} = 0V, T_C = 125°C$ - Forward Transconductance $V_{GS} = 10V, I_D = 2.50\muA$ 3.0 Static Drain to Source On Resistance $V_{GS} = 10V, I_D = 2.25A$ - Output Capacitance $V_{SS} = 25V, V_{GS} = 0V$ - Input Capacitance $V_{CS} = 10V, I_D = 4.5A$ - Gate to Source Gate Charge $V_{SS} = 10V, I_D = 4.5A$ - Gate to Drain "Miller" Charge $V_{CS} = 10V, I_D = 4.5A$ - | $\begin{tabular}{ c c c c c } \hline I Characteristics $$T_{C} = 25^{\circ}C $$ unless otherwise noted $$ Min. Typ. there is the term of term $ | $\begin{tabular}{ c c c c c c } \hline IC haracteristics & Min. Typ. Max. \\ \hline Parameter & Test Conditions & Min. Typ. Max. \\ \hline teristics & & & & & & & & & & & & & & & & & & &$ |

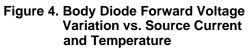


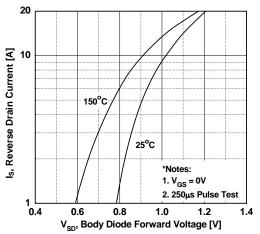




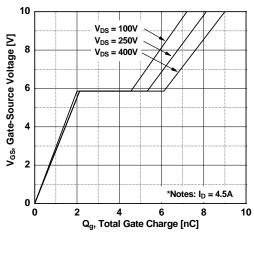




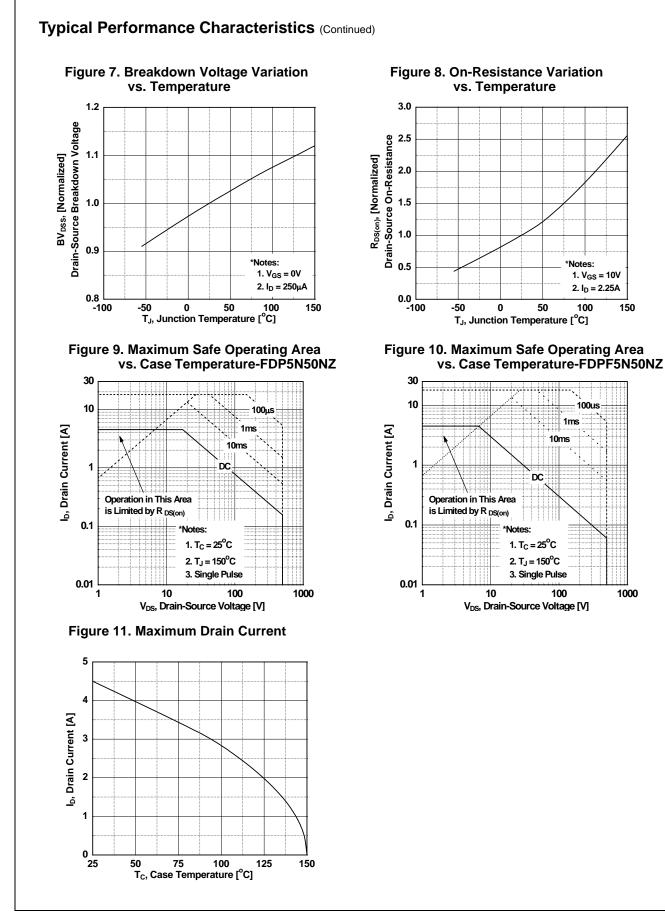






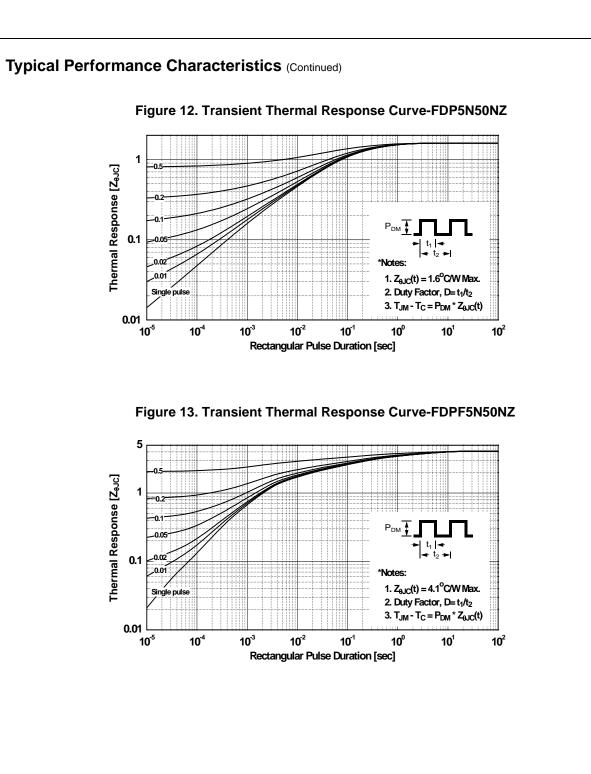


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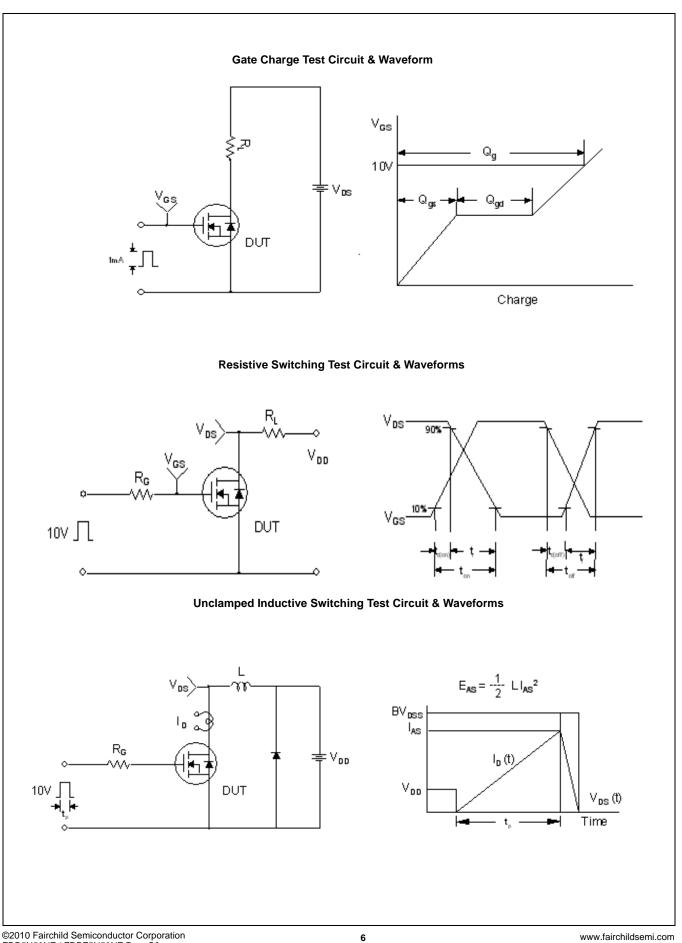
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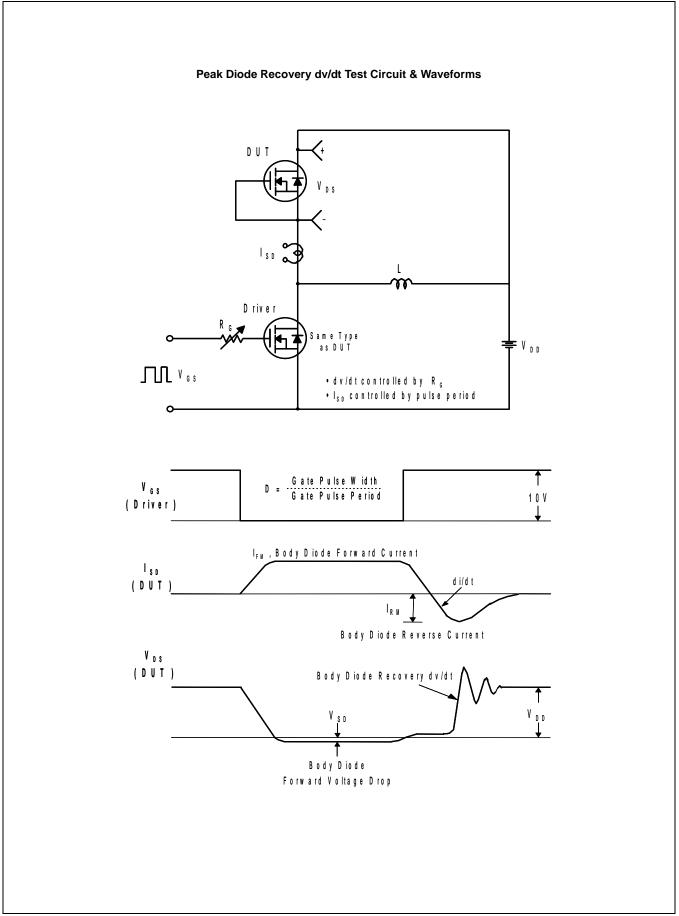
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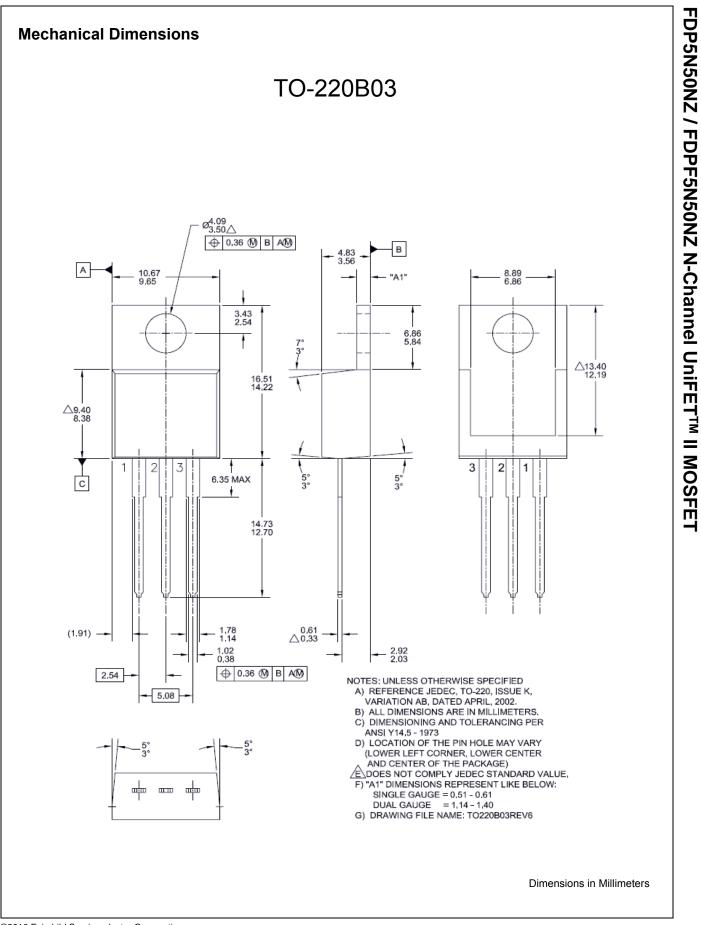


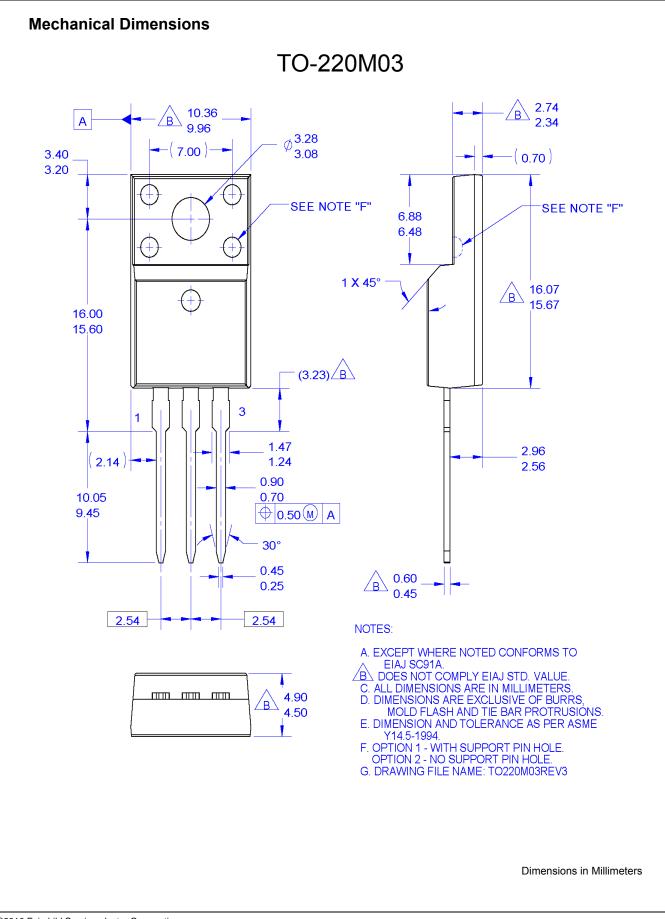
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